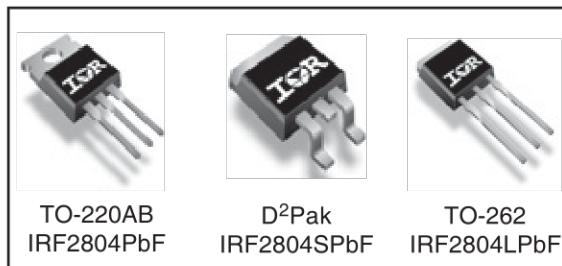
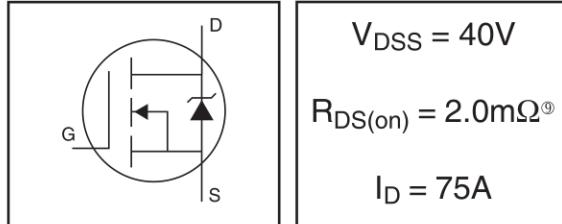


**AUTOMOTIVE MOSFET**

**IRF2804PbF**  
**IRF2804SPbF**  
**IRF2804LPbF**

HEXFET® Power MOSFET



**Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to  $T_{jmax}$
- Lead-Free

**Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	270	A
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V$ (See Fig. 9)	190	
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	75	
$I_{DM}$	Pulsed Drain Current ①	1080	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/ $^{\circ}C$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy (Thermally Limited) ②	540	mJ
$E_{AS}$ (tested)	Single Pulse Avalanche Energy Tested Value ③	1160	
$I_{AR}$	Avalanche Current ④	See Fig.12a,12b,15,16	A
$E_{AR}$	Repetitive Avalanche Energy ⑤		mJ
$T_J$	Operating Junction and	-55 to + 175	$^{\circ}C$
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

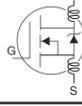
**Thermal Resistance**

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.50⑥	$^{\circ}C/W$
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	62	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state)⑦	—	40	

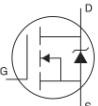
HEXFET® is a registered trademark of International Rectifier.

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**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

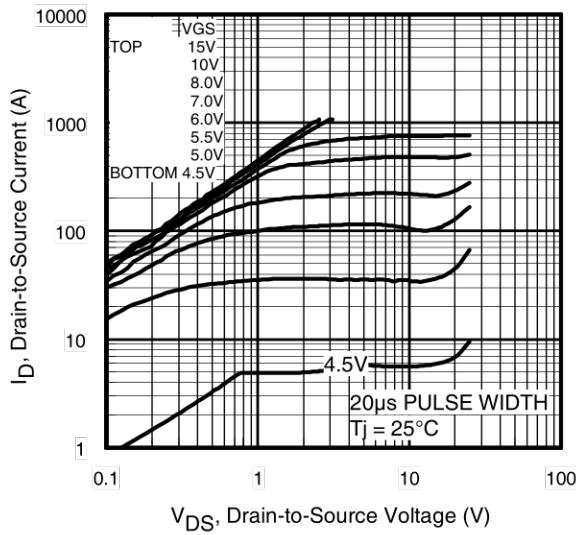
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	40	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.031	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS(on)}} \text{ SMD}$	Static Drain-to-Source On-Resistance	—	1.5	2.0	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 75\text{A}$ ④
$R_{\text{DS(on)}} \text{ TO-220}$	Static Drain-to-Source On-Resistance	—	1.8	2.3	$\text{m}\Omega$	$V_{GS} = 10V, I_D = 75\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$g_{fs}$	Forward Transconductance	130	—	—	S	$V_{DS} = 10V, I_D = 75\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{DS} = 40V, V_{GS} = 0V$
		—	—	250	$\mu\text{A}$	$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-200	nA	$V_{GS} = -20V$
$Q_g$	Total Gate Charge	—	160	240	nC	$I_D = 75\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	41	62	nC	$V_{DS} = 32V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	66	99	nC	$V_{GS} = 10V$ ④
$t_{d(\text{on})}$	Turn-On Delay Time	—	13	—	ns	$V_{DD} = 20V$
$t_r$	Rise Time	—	120	—	ns	$I_D = 75\text{A}$
$t_{d(\text{off})}$	Turn-Off Delay Time	—	130	—	ns	$R_G = 2.5\Omega$
$t_f$	Fall Time	—	130	—	ns	$V_{GS} = 10V$ ④
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—	nH	
$C_{iss}$	Input Capacitance	—	6450	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	1690	—	pF	$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	—	840	—	pF	$f = 1.0\text{MHz}$ , See Fig. 5
$C_{oss}$	Output Capacitance	—	5350	—	pF	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
$C_{oss}$	Output Capacitance	—	1520	—	pF	$V_{GS} = 0V, V_{DS} = 32V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	2210	—	pF	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V$

**Diode Characteristics**

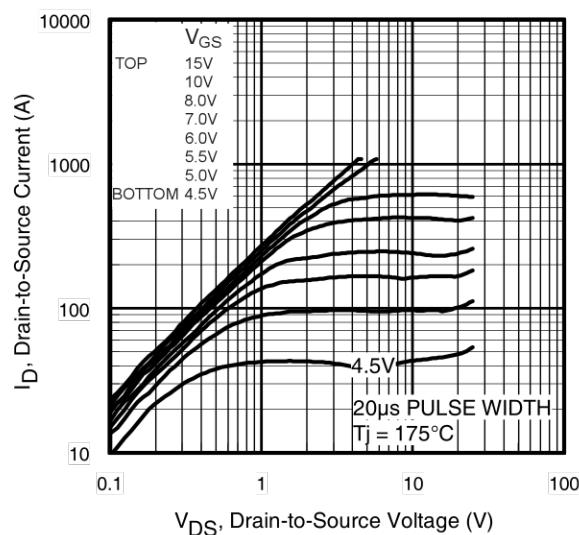
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	270	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	1080	A	
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 75\text{A}, V_{GS} = 0V$ ④
$t_{rr}$	Reverse Recovery Time	—	56	84	ns	$T_J = 25^\circ\text{C}, I_F = 75\text{A}, V_{DD} = 20V$
$Q_{rr}$	Reverse Recovery Charge	—	67	100	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

**Notes:**

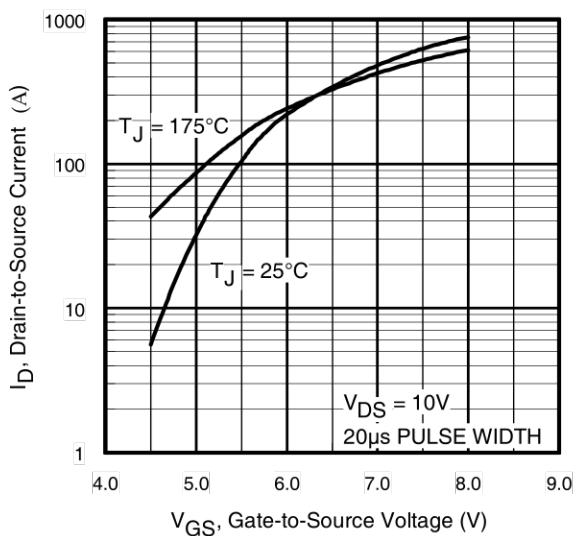
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{J\text{max}}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L=0.24\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 75\text{A}$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value.
- ③  $I_{SD} \leq 75\text{A}$ ,  $di/dt \leq 220\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ④ Pulse width  $\leq 1.0\text{ms}$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss \text{ eff.}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑥ Limited by  $T_{J\text{max}}$ , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑦ This value determined from sample failure population. 100% tested to this value in production.
- ⑧ This is applied to D<sup>2</sup>Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- ⑨ Max  $R_{\text{DS(on)}}$  for D<sup>2</sup>Pak and TO-262 (SMD) devices.
- ⑩ TO-220 device will have an  $R_{th}$  value of  $0.45^\circ\text{C}/\text{W}$ .



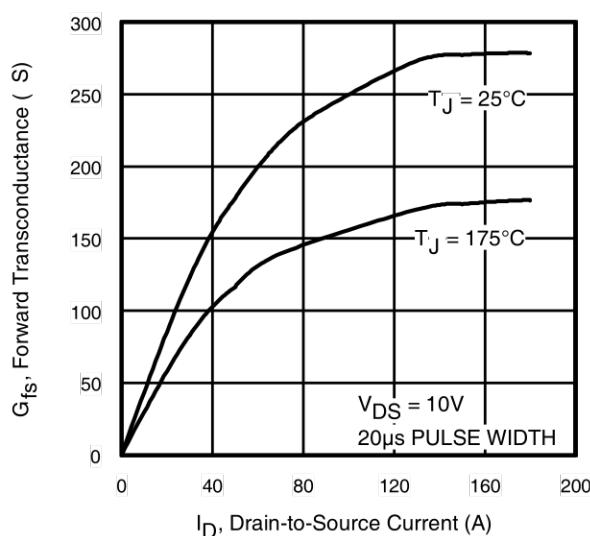
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



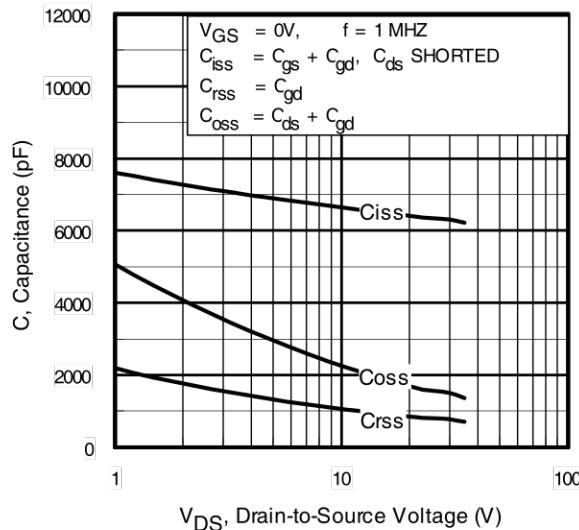
**Fig 3.** Typical Transfer Characteristics



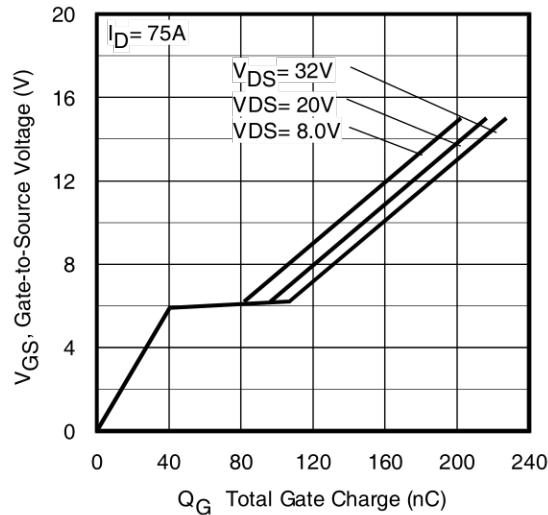
**Fig 4.** Typical Forward Transconductance vs. Drain Current

# IRF2804/S/LPbF

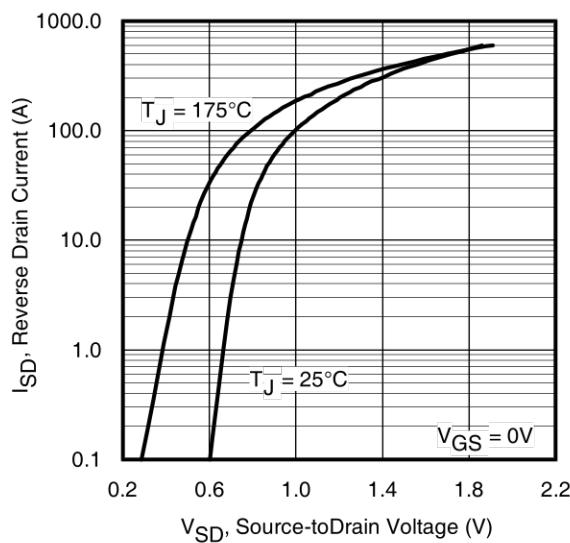
International  
**IR** Rectifier



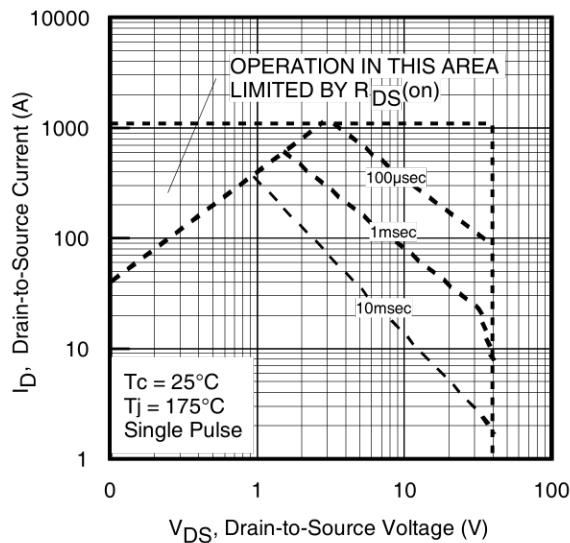
**Fig 5.** Typical Capacitance vs.  
Drain-to-Source Voltage



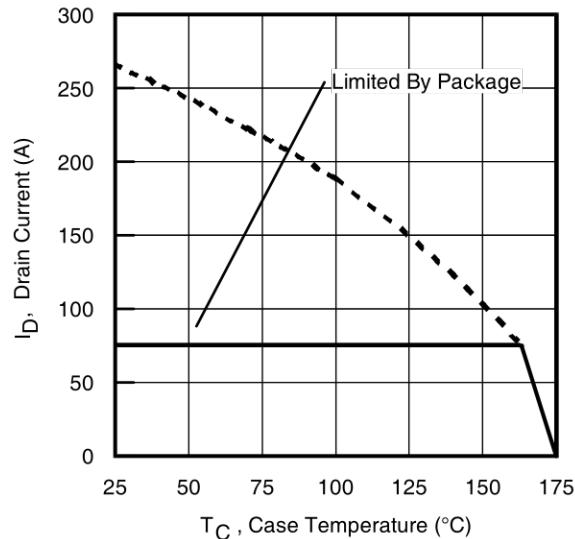
**Fig 6.** Typical Gate Charge vs.  
Gate-to-Source Voltage



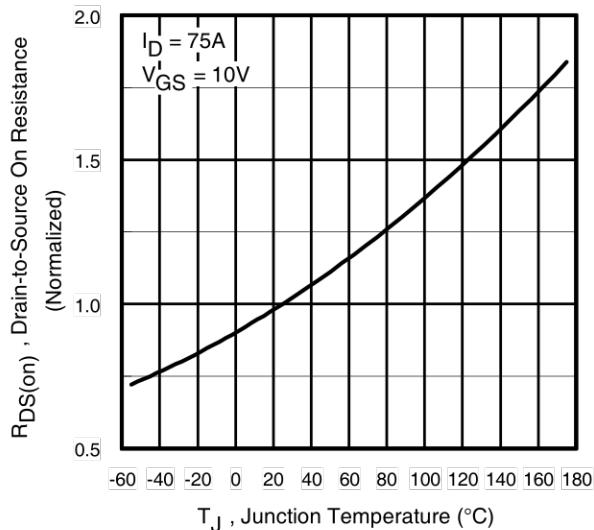
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



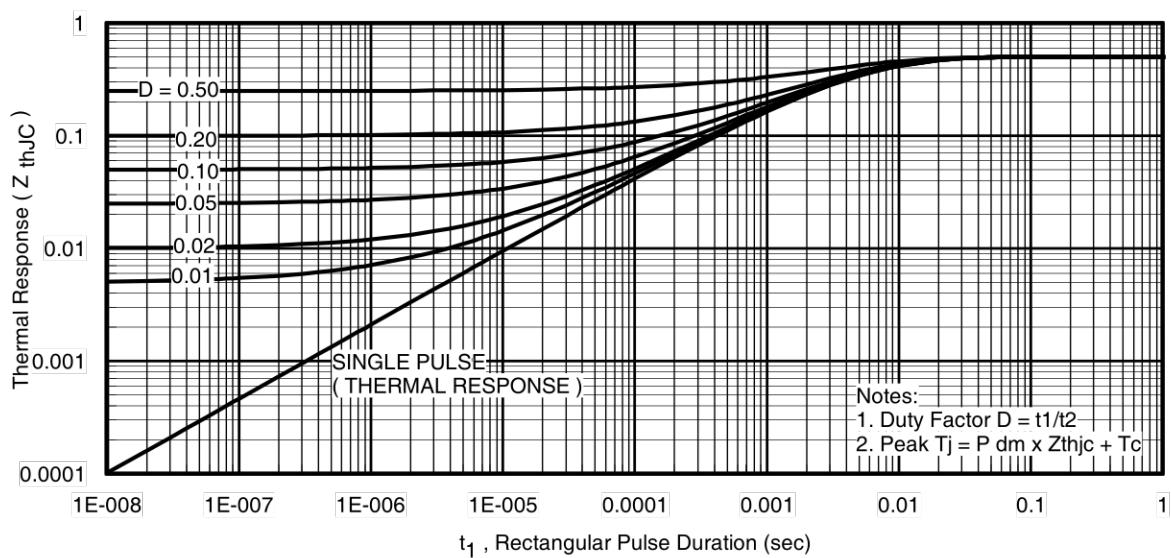
**Fig 8.** Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current vs.  
Case Temperature



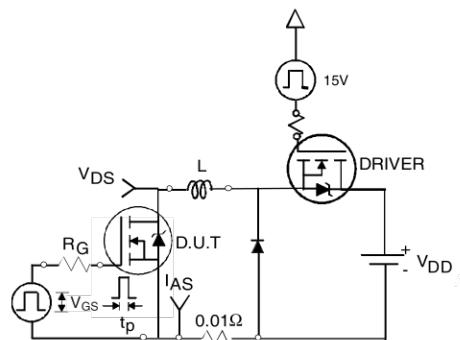
**Fig 10.** Normalized On-Resistance  
vs. Temperature



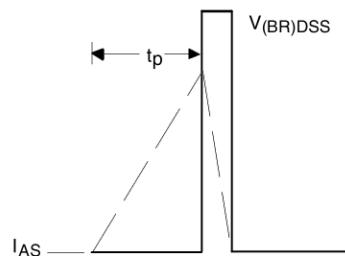
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

# IRF2804/S/LPbF

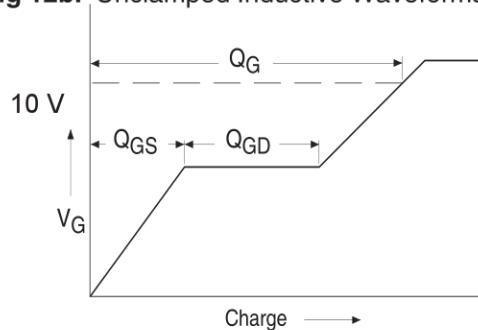
International  
Rectifier



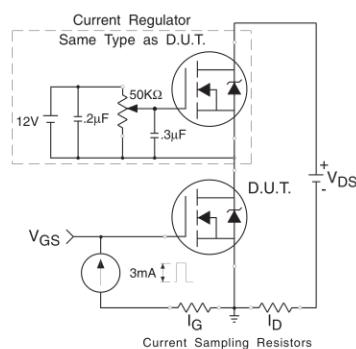
**Fig 12a.** Unclamped Inductive Test Circuit



**Fig 12b.** Unclamped Inductive Waveforms

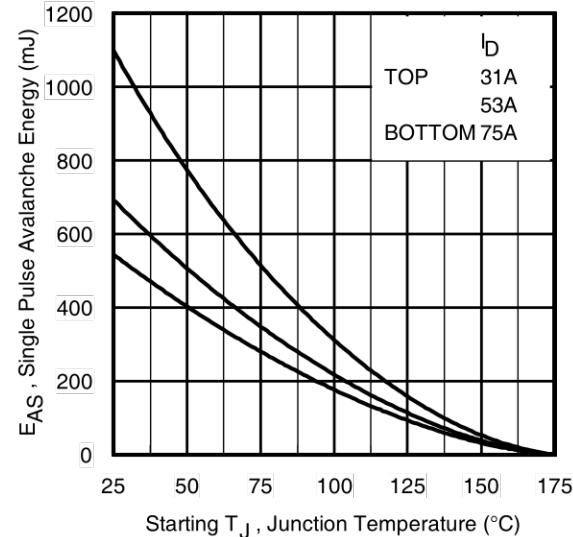


**Fig 13a.** Basic Gate Charge Waveform

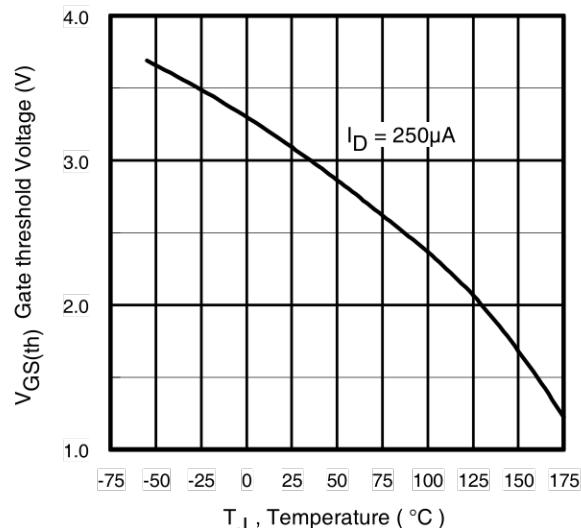


**Fig 13b.** Gate Charge Test Circuit

6

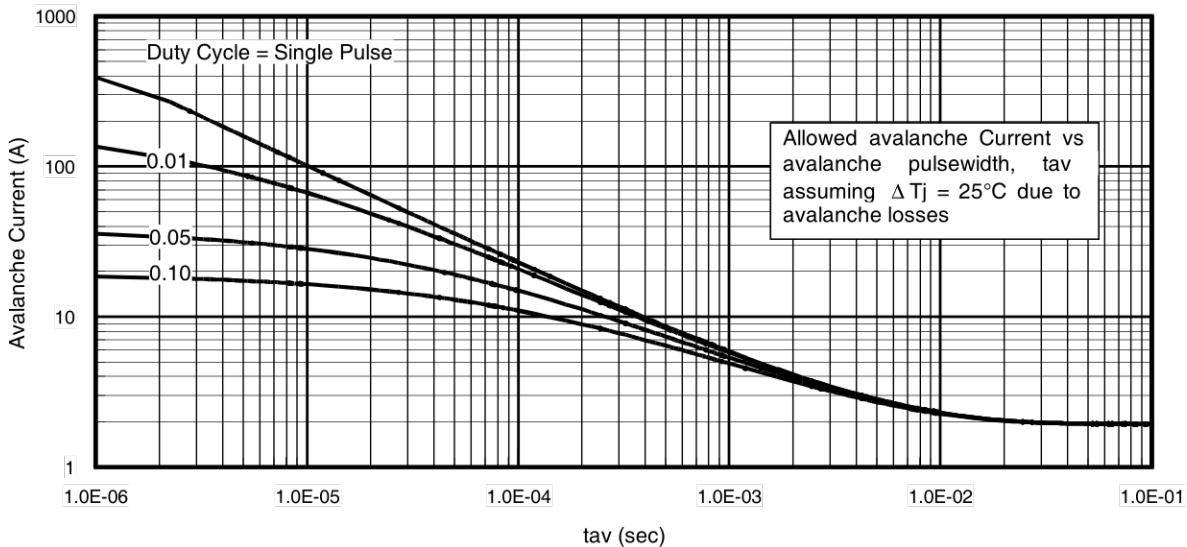


**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

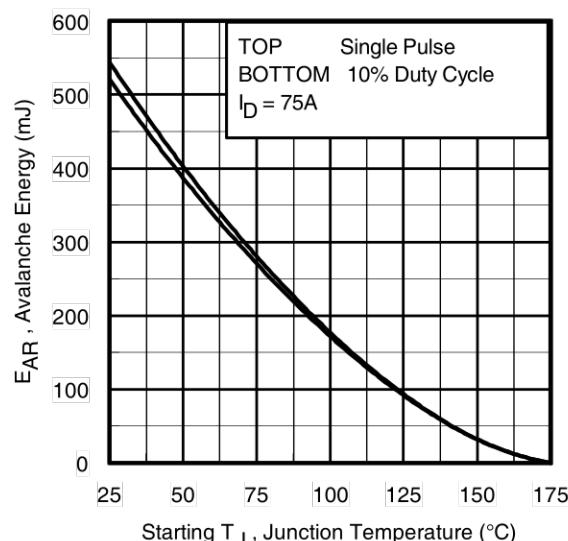


**Fig 14.** Threshold Voltage vs. Temperature

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**Fig 15.** Typical Avalanche Current Vs.Pulsewidth



**Fig 16.** Maximum Avalanche Energy  
vs. Temperature

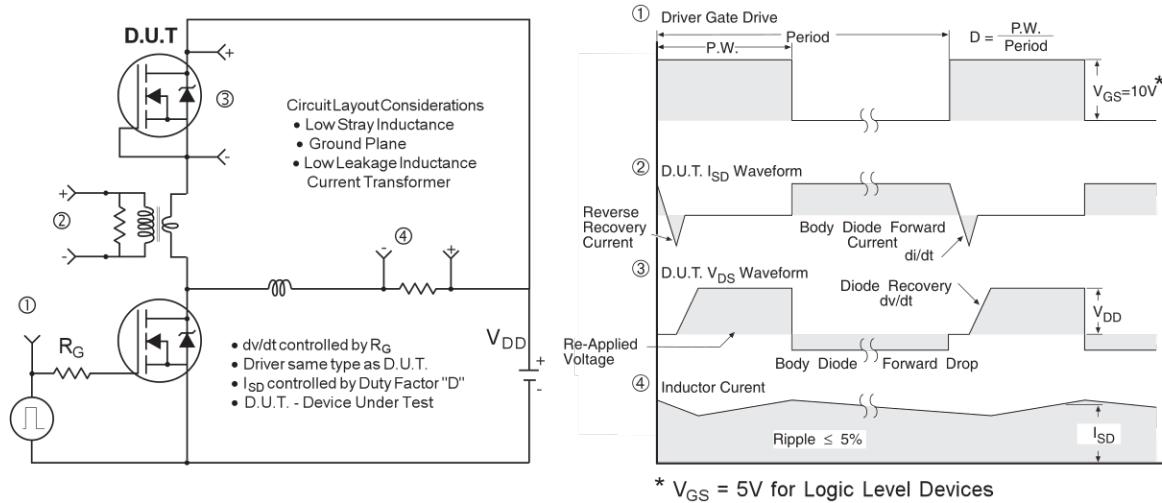
**Notes on Repetitive Avalanche Curves , Figures 15, 16:  
(For further info, see AN-1005 at [www.irf.com](http://www.irf.com))**

1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as  $25^\circ\text{C}$  in Figure 15, 16).
- $t_{av}$  = Average time in avalanche.
- D = Duty cycle in avalanche =  $t_{av} \cdot f$
- $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11

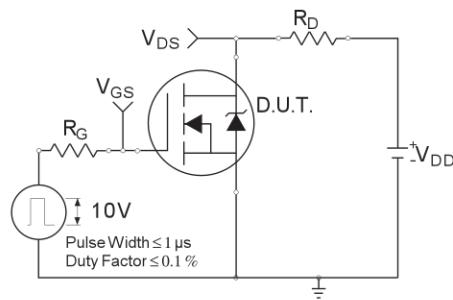
$$P_{D(ave)} = 1/2 ( 1.3 \cdot BV \cdot I_{av} ) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

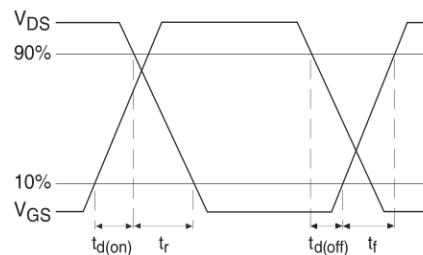
$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$



**Fig 17.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



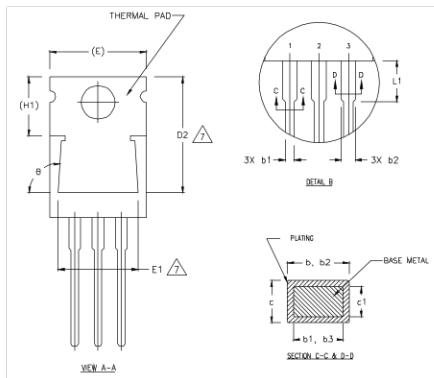
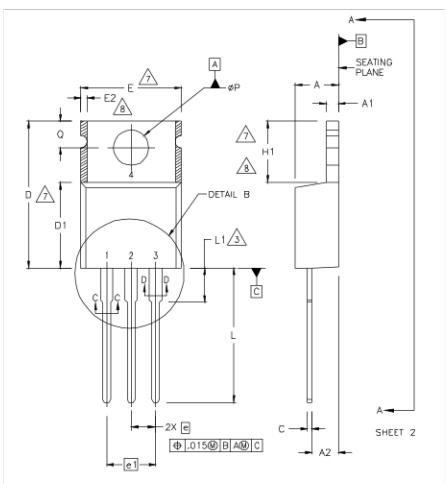
**Fig 18a.** Switching Time Test Circuit



**Fig 18b.** Switching Time Waveforms

## TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
2. DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
3. LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
4. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
5. DIMENSION b1 & c1 APPLY TO BASE METAL ONLY.
6. CONTROLLING DIMENSION : INCHES.
7. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
8. DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRRREGULARITIES ARE ALLOWED.

LEAD ASSIGNMENTS

- HEXFET  
1.- GATE  
2.- DRAIN  
3.- SOURCE

IGBTs, CoPack

- 1.- GATE  
2.- COLLECTOR  
3.- Emitter

DIODES

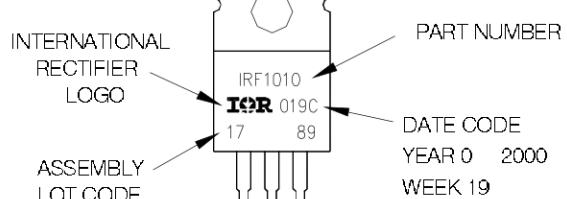
- 1.- ANODE/OPEN  
2.- CATHODE  
3.- ANODE

SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	3.56	4.82	.140	.190		
A1	0.51	1.40	.020	.055		
A2	2.04	2.92	.080	.115		
b	0.38	1.01	.015	.040		
b1	0.38	0.96	.015	.038		
b2	1.15	1.77	.045	.070		
b3	1.15	1.73	.045	.068		
c	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8.38	9.02	.330	.355		
D2	12.19	12.88	.480	.507	7	
E	9.66	10.66	.380	.420	4,7	
E1	8.38	8.89	.330	.350	7	
e	2.54 BSC		.100 BSC			
e1	5.08		.200 BSC			
H1	5.85	6.55	.230	.270	7,8	
L	12.70	14.73	.500	.580		
L1	—	6.35	—	.250	3	
ØP	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		
Ø	90°-93°		90°-93°			

## TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010  
LOT CODE 1789  
ASSEMBLED ON WW 19, 2000  
IN THE ASSEMBLY LINE "C"

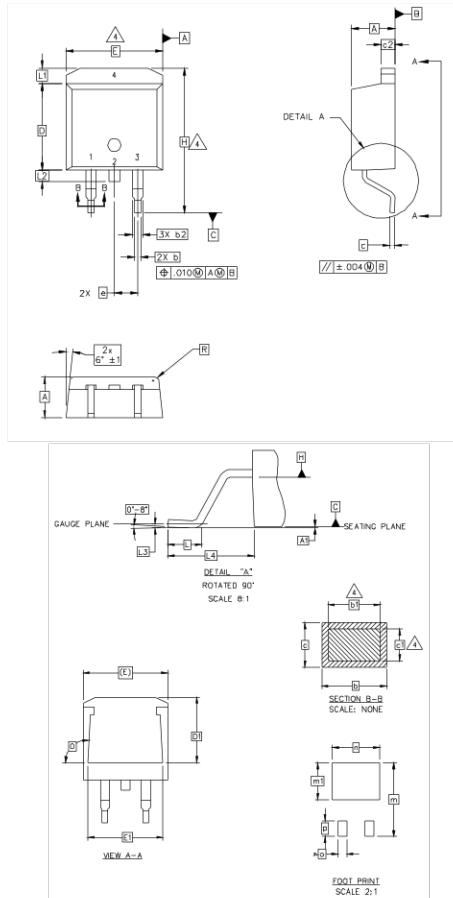
Note: "P" in assembly line position indicates "Lead - Free"



# IRF2804/S/LPbF

## D<sup>2</sup>Pak Package Outline

Dimensions are shown in millimeters (inches)



**NOTES:**

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES]
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
4. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
5. CONTROLLING DIMENSION: INCH.

S Y M B O L	DIMENSIONS		N O T E S
	MILLIMETERS	INCHES	
	MIN.	MAX.	
A	4.06	4.83	.160 .190
A1	0.00	0.254	.000 .010
b	0.51	0.99	.020 .039
b1	0.51	0.89	.020 .035
b2	1.14	1.78	.045 .070
c	0.38	0.74	.015 .029
c1	0.38	0.58	.015 .023
c2	1.14	1.65	.045 .065
D	8.51	9.65	.335 .380
D1	6.86		.270
E	9.65	10.57	.380 .420
E1	6.22		.245
e	2.54	BSC	.100 BSC
H	14.61	15.88	.575 .625
L	1.78	2.79	.070 .110
L1		1.65	.065
L2	1.27	1.78	.050 .070
L3	0.25	BSC	.010 BSC
L4	4.78	5.28	.188 .208
m	17.78		.700
m1	8.89		.350
n	11.43		.450
o	2.08		.082
p	3.81		.150
R	0.51	0.71	.020 .028
θ	90°	93°	.90° .93°

**LEAD ASSIGNMENTS**

**HEXFET**

- 1. GATE
- 2, 4. - DRAIN
- 3. - SOURCE

**IGBTs, CoPACK**

- 1. - GATE
- 2, 4. - COLLECTOR
- 3. - Emitter

**DIODES**

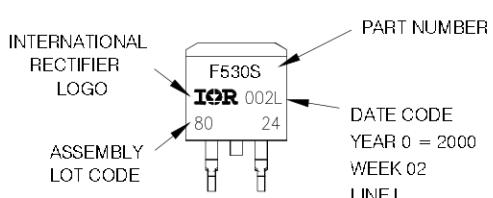
- 1. - ANODE \*
- 2, 4. - CATHODE
- 3. - ANODE

\* PART DEPENDENT.

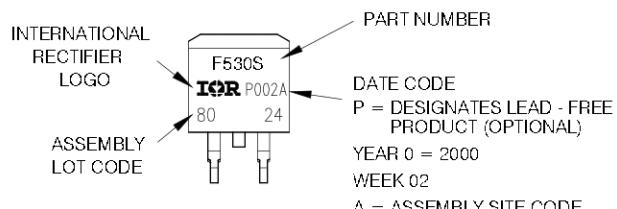
## D<sup>2</sup>Pak Part Marking Information

EXAMPLE: THIS IS AN IRF530S WITH  
LOT CODE 8024  
ASSEMBLED ON WW 02, 2000  
IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line position  
indicates "Lead - Free"

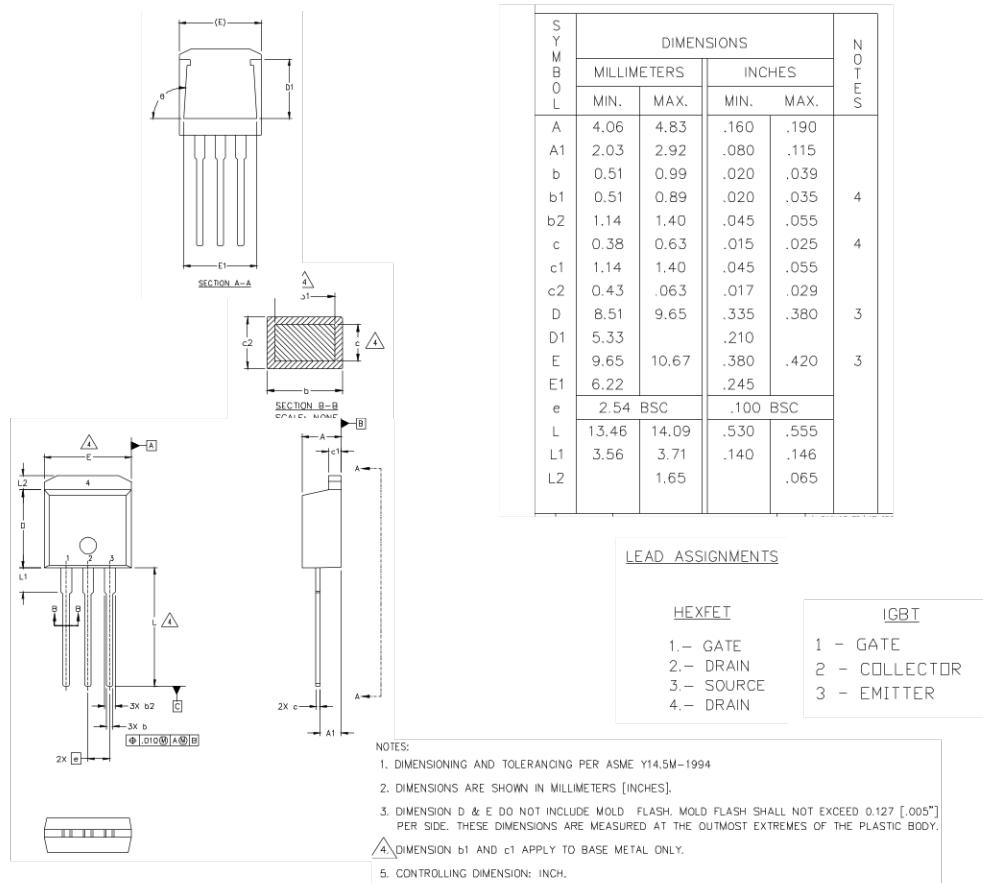


OR



## TO-262 Package Outline

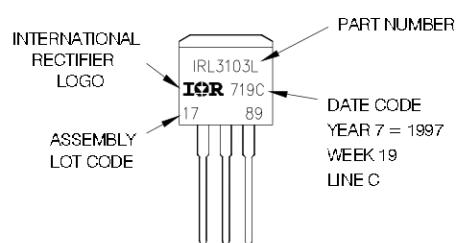
Dimensions are shown in millimeters (inches)



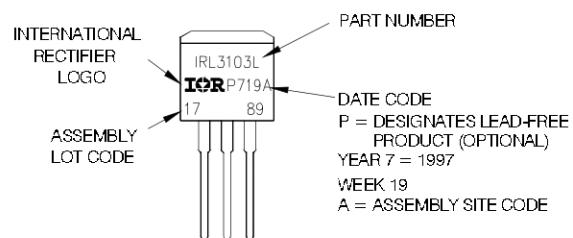
## TO-262 Part Marking Information

EXAMPLE: THIS IS AN IRL3103L  
LOT CODE 1789  
ASSEMBLED ON WW 19, 1997  
IN THE ASSEMBLY LINE C

Note: P in assembly line position indicates Lead-Free



OR

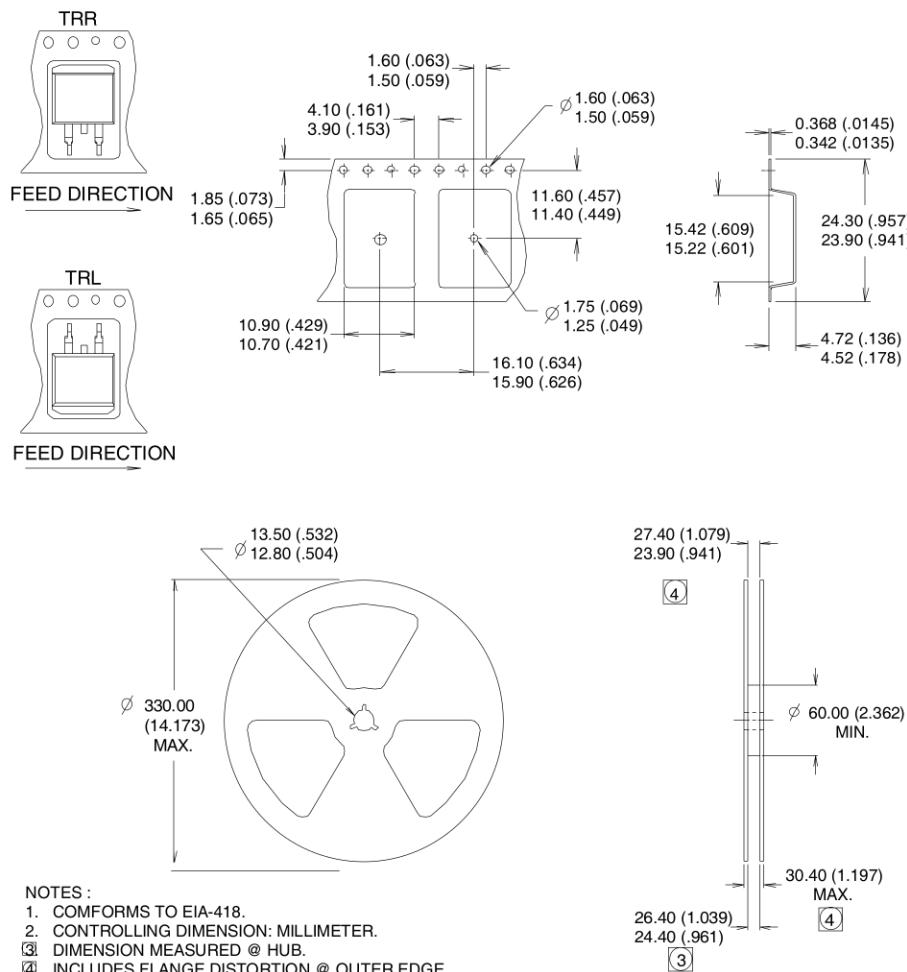


# IRF2804/S/LPbF

International  
**IR** Rectifier

## D<sup>2</sup>Pak Tape & Reel Information

Dimensions are shown in millimeters (inches)



**TO-220AB package is not recommended for Surface Mount Application.**

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Automotive [Q101] market.  
Qualification Standards can be found on IR's Web site.

International  
**IR** Rectifier

**IR WORLD HEADQUARTERS:** 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
TAC Fax: (310) 252-7903

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Note: For the most current drawings please refer to the IR website at:  
<http://www.irf.com/package/>